

1 [0081]

**ABSTRACT OF THE DISCLOSURE**

2 [0082] The present disclosure pertains to a method of preparing a test specimen for testing  
3 of the bonding strength of a layer of additive material to a crystalline substrate, or testing of the  
4 bonding strength of one layer of additive material to a second layer of additive material, where  
5 both layers of additive material overlie a crystalline substrate. The method includes both test  
6 specimen "cutting" from a large sample of material and preparation of an individual test  
7 specimen for four-point adhesion testing. Also described is a fixture which is useful for  
8 cutting the individual test specimen from the large sample of material.